

Form PTO-849

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
30-5004DIV2SERIAL NO.  
09/912,652LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Vladimir SegalFILING DATE  
July 24, 2001GROUP  
1742

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HW	AA	3,849,212	11-1974	Thornburg			
HW	AB	5,766,380	06-1998	Lo et al.			
HW	AC	6,123,896	09-2000	Meeks, III et al.			
HW	AD	3,653,981	04-1972	Watanabe et al.			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

RECEIVED  
 OCT 4 2002  
 TC 1700

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
HW	AM	03-082773	08.04.1991	Japan (abstract only)				
HW	AN	08-134606	28.05.1996	Japan (abstract only)				
	AO							
	AP							
	AQ							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

HW	AR		Material Evaluation Report, Ingot No. T891C, 03/25/98, 1 page.
	AS		
	AT		

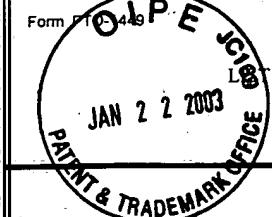
EXAMINER *Henry S. Wilhite*

DATE CONSIDERED

3/6/03

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

EV182662301



U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
30-5004DIV2

SERIAL NO.  
09/912,652

LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT  
Vladimir Segal et al.

FILING DATE  
July 24, 2001

GROUP  
1742

RECEIVED  
JAN 23 2003  
TC 1700

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HW	AA	5,171,379	12/1992	Kumar et al.			
HW	AB	5,722,165	03/1998	Kobayashi et al.			
HW	AC	4,517,032	05/1985	Goto et al.			
HW	AD	5,772,795	06/1998	Lally et al.			
HW	AE	6,221,178	04/2001	Torizuka et al.			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
HW	AM	252,442	09.06.1960	Australia				
HW	AN	57-106525 A 55-199764	12/1980	Japan				
	AO							
	AP							
	AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

HW	AR	Hughes et al., "Grain Subdivision and the Development of Local Orientations in Roiled Tantalum" Tantalum, The Minerals, Metals & Materials Society, 1996, pgs. 257-262. (Year is sufficiently early so that the month is not an issue.)
HW	AS	Arli, Jr., "Sulfonation and Sulfonation to Thorium and Thorium Compounds" Kirk-Othmer Encyclopedia of chemical Technology vol. 22, pp. 541-564, (1993, Year is sufficiently early so that the month is not an issue).
HW	AT	Kirkbride et al., "The Effect of Yttrium on the Recrystallization and Grain Growth of Tantalum", J. Less-Common Metals, vol. 9, pp. 393-408, 1965. (Year is sufficiently early so that the month is not an issue.)

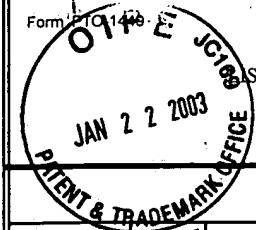
EXAMINER

*Henry S. Miller-HF*

DATE CONSIDERED

*3/6/03*

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
30-5004DIV1

SERIAL NO.  
09/912,476

LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT  
Vladimir Segal et al.

FILING DATE  
July 24, 2001

GROUP  
1742

RECEIVED  
JAN 23 2003  
TC 1700

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AB							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AC	NW	National Research Corporation Press Release, pgs. 1-4, July 1964.					
	AD	NW	National Research Corporation Data Sheet "SGS Tantalum", pgs. 1-7, no date.					
	AD	NW	ASTM Standard Specification for Tantalum and Tantalum Alloy Plate, Sheet, and Strip, pgs. 558-561, 1992. (Year is sufficiently early so that the month is not an issue.)					
	AE	NW	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Materials Research Society Symposium Proceedings, vol. 322, pgs. 413-422, 1994. (Year is sufficiently early so that the month is not an issue.)					
	-AF-	NW	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Refractory Metals & Hard Materials, vol. 12, pgs. 35-40, 1994. (Year is sufficiently early so that the month is not an issue.)					
	AG	NW	Klein et al., "Inhomogeneous Textures in Tantalum Sheets" Materials Science Forum, vol. 157-162, pgs. 1423, (1994). (Year is sufficiently early so that the month is not an issue.)					
	AH	NW	Clark et al., "Influence of Transverse Rolling on the Microstructural and Texture Development in Pure Tantalum", Metallurgical Transactions, vol. 23A, pgs. 2183-2191, August 1992.					
	AI	NW	Raabe, et al., "Texture and Microstructure of Rolled and Annealed Tantalum", Materials Science and Technology, Vol. 10, pgs. 299-305, April 1994.					
	AJ	NW	Wright et al., "Texture Gradient Effects in Tantalum", International Conference on Textures of Materials, 7 pgs., September 1993.					
	AK	NW	Wright et al., "Textural and Microstructural Gradient Effects on the Mechanical Behavior of a Tantalum Plate", Metallurgical Transactions A, 25A (1994), pgs. 1-17. (Year is sufficiently early so that the month is not an issue.)					
	AL	NW	Clark et al., "Effect of Processing Variables on Texture and Texture Gradients in Tantalum", Metallurgical Transactions A, Vol. 22A, September 1991, pgs. 2039-2047.					
	AM	NW	Kumar et al., "Corrosion Resistant Properties of Tantalum" Corrosion 95, Paper No. 253, 14 pages. (No date)					
	AN							
	AO	NW	V.M. Segal, "Materials Processing by Simple Shear", Materials Science and Engineering A, Volume 197, 1995, pgs. 157-164. (Year is sufficiently early so that the month is not an issue.)					
	AP							

EXAMINER *Shay S. White, III*

DATE CONSIDERED

3/6/03

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.